# Joint and Marginal Probability Analysis of Markov Random Field Networks for Digital Logic Circuits

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#### Conference

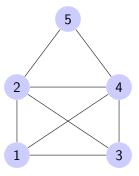
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### Introduction

- Nanoscale electronic circuits are suffering from both manufacturing defects and transient faults.
- Since, the integrated circuits are scaling to nano-level, they are expected to face high computing errors.
- Markov Random Field modelling is one approach to achieve noise-tolerance.

## Cliques

- A clique is a complete subgraph of a given graph.
- A maximal clique is a clique that cannot be extended by including one more adjacent vertex.



Markov network

# Joint Probability of MRF

#### Gibbs distribution

A Gibbs distribution on the graph G takes the form:

$$\Pr(X) = \frac{1}{Z} \prod_{c \in C} \phi_c(x_c) \tag{1}$$

$$\phi_c(x_c) = e^{-\frac{U_c(x_c)}{kT}} \tag{2}$$

 The Hammersley-Clifford theorem states that the joint probability distribution of any MRF can be written as a Gibbs distribution, and furthermore that for any Gibbs distribution there exists an MRF for which it is the joint.

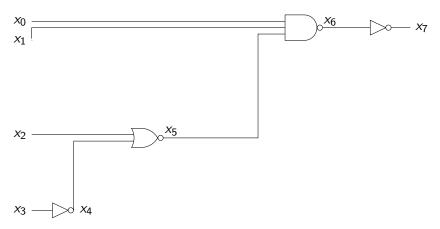
# Marginal Probability

 We fix the value of one or more variables and sum it over non-fixed variables.

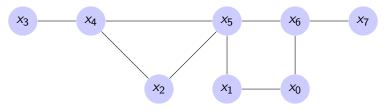
$$\Pr(X = x) = \sum_{y} \Pr(X = x, Y = y)$$
 (3)

$$=\sum_{V}\Pr\left(X=x|Y=y\right)\Pr\left(Y=y\right)\tag{4}$$

# Computing Joint Probability



M3 module of C432 Interrupt Controller



#### Dependence graph of the test circuit

Cliques:  $\{x_3, x_4\}, \{x_2, x_4, x_5\}, \{x_0, x_1, x_5, x_6\}, \{x_6, x_7\}$ 

<i>x</i> <sub>0</sub>	<i>x</i> <sub>1</sub>	<i>X</i> 5	<i>x</i> <sub>6</sub>	f
<i>x</i> <sub>0</sub>	0	<i>x</i> <sub>5</sub>	<i>x</i> <sub>6</sub>	1
0	0	0	0	0
0	0	1	1	1
0	0	1	0	0
0	1	0	1	1
0	1	0	0	0
0	1	1	1	1
0	1	1	0	0

<i>x</i> <sub>0</sub>	<i>x</i> <sub>1</sub>	<i>X</i> 5	<i>x</i> <sub>6</sub>	f
1 X <sub>0</sub>	0	0	1	1
1	0	0	0	0
1	0	1	1	1
1	0	1	0	0
1	1	0	1	1
1	1	0	0	0
1	1	1	0	1
1	1	1	1	0

Logic Compatibility Function for NAND

We will compute the clique energy function for  $\{x_0, x_1, x_5, x_6\}$ 

$$U_c = -\sum$$
 (Valid minterms  $(f=1)$  in the Logic Compatibility Function) (5)

$$= -\left[x_0'x_1'x_5'x_6 + x_0'x_1'x_5x_6 + x_0'x_1x_5'x_6 + x_0'x_1x_5x_6 + x_0x_1'x_5x_6 + x_0x_1'x_5x_6 + x_0x_1x_5x_6'\right]$$
(6)

$$=2x_0x_1x_5x_6-x_0x_1x_5-x_6 (7)$$

### Clique energy functions for NOT and NOR gates

NOT 1	$2x_3x_4 - x_3 - x_4$
NOR	$x_2x_4 + 2x_4x_5 + 2x_2x_5 - 2x_2x_4x_5 - x_2 - x_4 - x_5$
NOT 2	$2x_6x_7 - x_6 - x_7$

Now, we will compute the joint probability

$$\Pr(x_{0}, x_{1}, x_{2}, x_{3}, x_{4}, x_{5}, x_{6}, x_{7}) = \frac{1}{Z} \left( e^{\frac{-U_{c}(NOT 1)}{kT}} e^{\frac{-U_{c}(NAND)}{kT}} e^{\frac{-U_{c}(NOR)}{kT}} e^{\frac{-U_{c}(NOT 2)}{kT}} e^{\frac{-U_{c}(NOT 2)}{kT}} \right)$$
(8)

$$=\frac{1}{Z}exp\left[\frac{x_2+x_3+2x_4+x_5+2x_6+x_7-x_2x_4-2x_2x_5-2x_3x_4}{-2x_4x_5-2x_6x_7+x_0x_1x_5+2x_2x_4x_5-2x_0x_1x_5x_6}{kT}\right]$$

- Following the joint probability calculation, we need to find the node label combinations that maximize its value.
- The maximum value is  $\frac{1}{Z}e^{\frac{4}{kT}}$ . There are 16 node label combinations.
- These 16 combinations are same as the circuit's truth table, which shows that joint probability is maximum only for correct logic combinations.
- For the rest of the combinations, the joint probability is lower.

### Design Principle of Joint Probability

For perfect logic operation of a circuit, we need to design our circuit such that joint probability of the circuit remains maximum at all times.

# Computing Marginal Probability

- For computing the probability of the (intermediate and output) nodes, we will use the belief propagation algorithm.
- We will assign PDFs to all inputs and cliques.

$$\Pr(x_7) = f_0 f_1 f_2 f_3 f_4 f_5 f_6 f_7 \tag{10}$$

### PDFs for Inputs and Cliques

Input	PDF	Clique	PDF
<i>x</i> <sub>0</sub>	$f_0(s_0)$	$\{x_3, x_4\}$	$f_4(x_3,x_4)$
<i>x</i> <sub>1</sub>	$f_1(s_1)$	$\{x_2, x_4, x_5\}$	$f_5(x_2, x_4, x_5)$
<i>x</i> <sub>2</sub>	$f_2(s_2)$	$\{x_0, x_1, x_5, x_6\}$	$f_6(x_0, x_1, x_5, x_6)$
<i>x</i> <sub>3</sub>	$f_3(s_3)$	$\{x_6, x_7\}$	$f_7(x_6, x_7)$

### Step 1: (Eliminating $x_3$ )

$$\Pr(x_4) = \sum_{x_3 \in \{0,1\}} \frac{1}{Z_1} e^{-\frac{U_c(\text{NOT } 1)}{kT}}$$
 (11)

$$=\frac{1}{Z_1}\left(e^{\frac{x_4}{kT}}+e^{\frac{1-x_4}{kT}}\right) \tag{12}$$

$$=f_8\left(x_4\right)\tag{13}$$

$$Pr(x_7) = f_0 f_1 f_2 f_5 f_6 f_7 f_8 \tag{14}$$

### Step 2: (Eliminating $x_2$ )

$$\Pr(x_5|x_4) = \sum_{x_2 \in \{0.1\}} \frac{1}{Z_2} e^{-\frac{U_c(NOR)}{kT}}$$
 (15)

$$=\frac{1}{Z_2}\left(e^{\frac{x_4+x_5-2x_4x_5}{kT}}+e^{\frac{1-x_5}{kT}}\right)$$
(16)

$$= f_9(x_4, x_5) (17)$$

$$Pr(x_7) = f_0 f_1 f_6 f_7 f_8 f_9 (18)$$

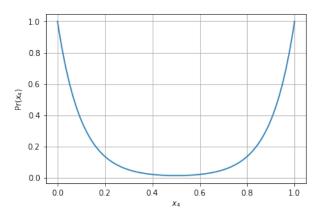


Figure: Plot of probability of  $x_4$  against  $x_4$ 

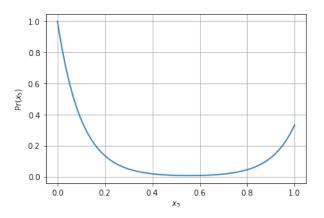


Figure: Plot of probability of  $x_5$  against  $x_5$ 

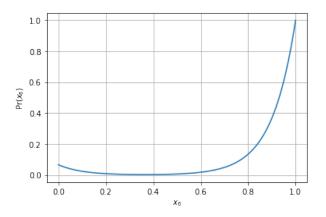


Figure: Plot of probability of  $x_6$  against  $x_6$ 

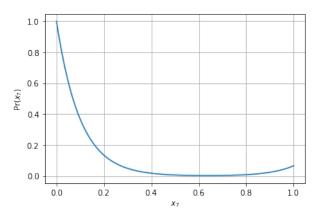


Figure: Plot of probability of  $x_7$  against  $x_7$ 

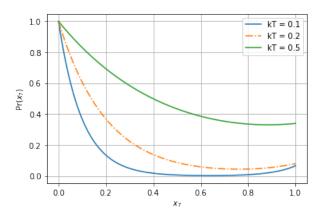


Figure: Plot of probability of  $x_7$  for different values of T

### Design Principle of Marginal Probability

The key to design a fault-tolerant circuit is to ensure a good heat removal system for the integrated circuit which would make the probability of intermediate states between '0' and '1' close to zero and maintain sufficient noise margin as well.